



**12500 TI Boulevard, MS 8640, Dallas, Texas 75243**

**PCN# 20130318000**  
**Qualification of Aizu as additional Fab site option for select devices**  
**in the CMOS7 process**  
**Change Notification / Sample Request**

**Date:** 3/20/2013  
**To:** MOUSER PCN

Dear Customer:

This is an announcement of a change to a device that is currently offered by Texas Instruments. The details of this change are on the following pages.

We request you acknowledge receipt of this notification within **30** days of the date of this notice. Lack of acknowledgement of this notice within 30 days constitutes acceptance of the change. If you require samples or additional data to support your evaluation, please request within 30 days.

The changes discussed within this PCN will not take effect any earlier than **90** days from the date of this notification, unless customer agreement has been reached on an earlier implementation of the change. This notification period is per TI's standard process.

This notice does not change the end-of-life status of any product. Should product affected be on a previously issued product withdrawal/discontinuance notice, this notification does not extend the life of that product or change the life time buy offering/discontinuance plan.

For questions regarding this notice, contact your local Field Sales Representative or the PCN Manager ([PCN\\_ww\\_admin\\_team@list.ti.com](mailto:PCN_ww_admin_team@list.ti.com)).

Sincerely,

PCN Team  
SC Business Services  
Phone: +1(214) 480-6037  
Fax: +1(214) 480-6659

**20130318000  
Attachment: 1**

**Products Affected:**

The devices listed on this page are a subset of the complete list of affected devices. According to our records, these are the devices that you have purchased within the past twenty-four (24) months. The corresponding customer part number is also listed, if available.

<b>DEVICE</b>	<b>CUSTOMER PART NUMBER</b>
LM10506TME/NOPB	null
LM3242TME/NOPB	LM3242TME/NOPB
LM3262TME/NOPB	null
LM3530UME-25A/NOPB	LM3530UME-25A NOPB
LM3530UME-40/NOPB	LM3530UME-40 NOPB

Technical details of this Product Change follow on the next page(s).

<b>PCN Number:</b>	20130318000			<b>PCN Date:</b>	03/20/2013	
<b>Title:</b>	Qualification of Aizu as an additional Fab Site for select devices in CMOS7 process					
<b>Customer Contact:</b>		PCN Manager	<b>Phone:</b>	+1(214)480-6037	<b>Dept:</b>	Quality Services
<b>*Proposed 1<sup>st</sup> Ship Date:</b>		06/20/2013	<b>Estimated Sample Availability:</b>	Date Provided at Sample request		
<b>Change Type:</b>						
<input checked="" type="checkbox"/>	Wafer Fab Site	<input type="checkbox"/>	Wafer Fab Materials	<input type="checkbox"/>	Wafer Fab Process	
<b>PCN Details</b>						
<b>Description of Change:</b>						
This change notification is to announce the addition of Aizu as a Fab site option for select devices in the CMOS7 Fab Process.						
Current Site/Process/Wafer Diameter		<b>Additional Site/Process/Wafer Diameter</b>				
MAINEFAB/CMOS7/200mm		AIZU/CMOS7/200mm				
<b>Reason for Change:</b>						
Continuity of supply.						
<b>Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):</b>						
None						
<b>Changes to product identification resulting from this PCN:</b>						
Shipment Labels:						
Current						
Chip Site	Chip site code (20L)		Chip country code (21L)			
MAINEFAB	CUA		USA			
New						
Chip Site	Chip site code (20L)		Chip country code (21L)			
AIZU	CU2		JPN			
Sample product shipping label (not actual product label)						
 <b>TEXAS INSTRUMENTS</b> MADE IN: Malaysia 2DC: 20: MSL 2 / 260C/1 YEAR SEAL DT MSL 1 / 235C/UNLIM 03/29/04 OPT: ITEM: 39 <b>LBL: 5A (L)T0:1750</b>		(1P) SN74LS07NSR (Q) 2000 (D) 0336 (31T) LOT: 3959047MLA (4W) TKY(1T) 7523483SI2 (P) (2P) REV: (V) 0033317 (20L) CS0: SHE (21L) CCO:USA (22L) AS0: MLA (23L) AC0: MYS				

<b>Product Affected:</b>			
LM10506TME-A/NOPB	LM3242TME/S7002949	LM3263TME/NOPB	LM3559TLX/S7002731
LM10506TME-C/NOPB	LM3242TME/S7003011	LM3263TMX/NOPB	LM3630ATME
LM10506TME-D/NOPB	LM3242TMX/NOPB	LM3530TME-40/NOPB	LM3630ATMX
LM10506TME/NOPB	LM3242TMX/S7002786	LM3530TMX-40/NOPB	LM3630TME/NOPB
LM10506TMX-A/NOPB	LM3242TMX/S7002949	LM3530UME-25A/NOPB	LM3630TMX/NOPB
LM10506TMX-C/NOPB	LM3242TMX/S7003011	LM3530UME-40/NOPB	LM3642TLE/NOPB
LM10506TMX-D/NOPB	LM3243TME/NOPB	LM3530UME-40B/NOPB	LM3642TLX/NOPB
LM10506TMX/NOPB	LM3243TMX/NOPB	LM3530UMX-25A/NOPB	LM3642TLE-LT/NOPB
LM10524TME/NOPB	LM3248TME/NOPB	LM3530UMX-25A/S7003079	LM3642TLX-LT/NOPB
LM10524TMX/NOPB	LM3248TMX/NOPB	LM3530UMX-40/NOPB	LP8552TLX-E00/S7002840

LM10526TME/NOPB	LM3262TME/NOPB	LM3530UMX-40B/NOPB	LP8552TLX-E00/S7002840
LM10526TMX/NOPB	LM3262TMX/NOPB	LM3559TLE/NOPB	LP8788DLE/NOPB
LM3242TME/NOPB	LM3262TMX/S1	LM3559TLX/NOPB	LP8788DLX/NOPB

## Reference Qualification Data: CMOS7 Process at AIZU

### Qualification Data: (Approved 12/17/2012)

This qualification has been developed for the validation of this change. The qualification data will validate that the proposed change meets the applicable released technical specifications.

#### Qualification Device: LP5521TM\_TL (MSL LEVEL1-260C)

#### Package Construction Details

Wafer Fab Site:	AIZU	Wafer Fab Process:	CMOS7 5V
Wafer Diameter:	200mm	Metallization:	Al .5%Cu
Passivation:	PECVDOX/NITRID		

#### Qualification: Plan Test Results

Reliability Test	Conditions	Sample Size / Fail		
		Lot#1	Lot#2	Lot#3
**Biased HAST	110C/85%RH (264 Hrs)	76 <sup>1</sup> /0	72 <sup>1</sup> /0	73 <sup>1</sup> /0
**Autoclave 121C	121C (96 Hrs)	77/0	77/0	77/0
**High Temp Storage Bake	150C (1000 Hrs)	77/0	-	-
ESD HBM	1000V	3/0	3/0	-
ESD CDM	250V	3/0	3/0	3/0
Latch-up	(per JESD78)	12/0	12/0	12/0
Power Cycle for Eprom	125C (10,000 Cyc)	77/0	77/0	77/0
High Temperature Data Retention	250C (82 Hrs)	77/0	77/0	77/0
Life Test	125C (1000 Hrs)	77/0	77/0	76 <sup>2</sup> /0
Temp Cycle	-40/125C (1068 Cyc)	74 <sup>3</sup> /0	77/0	77/0
Manufacturability (Assembly)	(per mfg. Site specification)	Pass	Pass	Pass
Manufacturability (Wafer Fab)	(per mfg. Site specification)	Pass	Pass	Pass

#### \*\*Preconditioning: MSL1@260C

Note 1: Sample size reduced due to non-valid failures, not related to process qualification

Note 2: Unit lost

Note 3: Solder joint fatigue failures occurred after 500 cycles, not related to process qualification

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	<a href="mailto:PCNAmericasContact@list.ti.com">PCNAmericasContact@list.ti.com</a>
Europe	<a href="mailto:PCNEuropeContact@list.ti.com">PCNEuropeContact@list.ti.com</a>
Asia Pacific	<a href="mailto:PCNAsiaContact@list.ti.com">PCNAsiaContact@list.ti.com</a>
Japan	<a href="mailto:PCNJapanContact@list.ti.com">PCNJapanContact@list.ti.com</a>